

# Jakub Krzesłowski

## **Lista publikacji z dnia 31 października 2014**

### **Książki i monografie**

1. Sitnik R., Krzesłowski J., Mączkowski G., **On reconstructing models of cultural heritage objects in terms of shape, color and appearance**, [w:] **Image Processing & Communications Challenges 3**, Choraś R., Springer-Verlag Berlin Heidelberg, 2011, s. 359-368
2. Sitnik R., Mączkowski G., Krzesłowski J., **Calculation methods for digital model creation based on integrated shape, color and angular reflectivity measurement**, [w:] **Digital Heritage**, Ioannides M., Fellner D., Georgopoulos A., Hadjimitsis D., Springer Berlin Heidelberg, 2010, s. 13–27
3. Sitnik R., Krzesłowski J., Mączkowski G., **Extending 3D Shape Measurement with Reflectance Estimation**, [w:] **Image Processing & Communications Challenges 2**, Choraś R., Springer-Verlag Berlin Heidelberg, 2010, s. 175–183

### **Publikacje w czasopismach**

1. Krzesłowski J., Sitnik R., Mączkowski G., 2012, **Multi-directional illumination : a novel 3D and BRDF approach in integrated heritage digitization**, International Journal of Heritage in the Digital Era 1(3): s. 421-441
2. Mączkowski G., Sitnik R., Krzesłowski J., 2012, **Integrated digitization method for cultural heritage objects**, Photonics Letters of Poland 4(2): s. 51-53
3. Sitnik R., Krzesłowski J., Mączkowski G., 2012, **Processing paths from integrating multimodal measurement of shape, color and BRDF**, International Journal Heritage in the Digital Era 1(1): s. 25-44
4. Sitnik R., Krzesłowski J., Mączkowski G., 2012, **Archiving shape and appearance of cultural heritage objects using structured light projection and multispectral imaging**, Optical Engineering 51(2): 021115
5. Mączkowski G., Krzesłowski J., Sitnik R., 2011, **Integrated Method for 3D Shape and Multispectral Color Measurement**, Journal of Imaging Science and Technology 55(3): 030502-(10)
6. Krzesłowski J., Sitnik R., Mączkowski G., 2011, **Integrated three-dimensional shape and reflection properties measurement system**, Applied optics 50(4): s. 532-541